Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,666	DEGUCHI ET AL.	
Examiner	Art Unit	
Joon H. Hwang	2166	

SEARCHED					
Class	Subclass	Date	Examiner		
707	3, 10	11/1/2006	JH		
707	100-104.1	11/1/2006	JH .		
	ii.				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
search-se	JSPAT text see search rintout(s)	11/1/2006	JH*	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor searched see search history printout(s) google, ieee, acm	11/1/2006	JH		
-				